

Search Notes

Application/Control No.

10/686,636

Examiner

Judson H. Jones

Applicant(s)/Patent under
Reexamination

TANAKA, YONETA

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	12	6/2/2005	JHJ
355	53,72	6/2/2005	JHJ
118	728,729	6/2/2005	JHJ
33	568,573	6/2/2005	JHJ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO BRS search search terms: wafer and stage same (piezo or piezoelect\$8) USPAT, PG PUB, EPO, JPO and Derwent	6/4/2005	JHJ